Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/677,566	DEY ET AL.
Examiner	Art Unit
Suk lin Kana	2610

SEARCHED				
Class	Subclass	Date	Examiner	
370	208	6/8/2007	SJK	
370	203	6/8/2007	SJK	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
·	DATE	EXMR		
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	6/8/2007	SJK		
Inventor name and Assignee search in PALM ExPO and EAST	6/8/2007	SJK		
Consulted with Chau Nguyen (SPE)	6/8/2007	sJK .		
Google (www.google.com)	6/8/2007	SJK		
(370/203.ccls. or 370/208.ccls. or 370/210.ccls. or 375/365.ccls. or 375/346.ccls.)	6/8/2007	SJK		
Consulted with Chau Nguyen (SPE)	10/22/2007	SJK		
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